

ORION® User Meeting Twente 2012

February 15th, 2012



Helium Ion Microscope
Next Generation Workstation for Nanoscale Research

Fee / Costs

The workshop is free of charge

Workshop Location

Eden Hotel De Broeierd Enschede
Hengelosestraat 725
7521 PA Enschede

Arranged by Carl Zeiss NTS GmbH
in cooperation with the University of Twente
and MESA+

UNIVERSITY OF TWENTE.

MESA+
INSTITUTE FOR NANOTECHNOLOGY

Carl Zeiss Nano Technology Systems
www.zeiss.de/microscopy

Room Reservation

There is the possibility to book a Hotel room in the "Eden Hotel De Broeierd Enschede" or in the "Conference hotel Drienerburght" via Carl Zeiss. The cost for the Eden Hotel is EUR 102,- and in the Drienerburght Hotel EUR 74,50,- per person and night, breakfast included. Please indicate with registration. Notice that we have a limited number of available rooms.

Hotel Address

Eden Hotel De Broeierd Enschede
Hengelosestraat 725
7521 PA Enschede

Conference hotel Drienerburght Enschede NL
University of Twente



We make it visible.

Wednesday 15th February, 2012

Eden Hotel De Broeierd Enschede (Diningroom 1 t/m 4)

08:30-08:45	Welcome, Carl Zeiss NTS	Carl Zeiss NTS
08:45-09:00	Welcome, University of Twente	Raoul van Gastel University of Twente
09:00-09:30	The Helium Ion Microscope: Status and News	Peter Gnauck Carl Zeiss NTS
09:30-10:00	Exploiting channeling in Helium Ion Microscopy	Gregor Hlawacek University of Twente
10:00-10:30	HIM of CNMs: Helium Ion Microscopy of Carbon Nano Membranes	Armin Götzhäuser University of Bielefeld
10:30-11:00	Coffee break	
11:00-11:30	Helium-ion Microscopy for nanoscale modification	Hongzhou Zhang CRANN Trinity College, Dublin
11:30-12:00	Using Helium and Neon Ion Beams for Sub-10-nm Lithography	Karl Berggren MIT
12:00-12:30	Imaging with secondary electrons – SEM and HIM compared	Lorenz Lechner Carl Zeiss NTS
12:30-13:00	Fabrication of nano-scale memristor crossbar devices and analysis of their switching mechanisms with the helium ion microscope	Doug Ohlberg Hewlett Packard Labs
13:00-14:00	Lunch	

14:00-14:30	Simulation of He-ion beam induced deposition	Paul Alkemade TU Delft
14:30-15:00	Helium Ion Milling of Solid-State Nanopores for Single-Molecule Detection	Adam Hall JSNN
15:00-15:30	Nano-engineering with helium ions	Diederik Maas TNO Science and Industry
15:30-16:00	Helium ion beam milling of thin film materials	Stuart Boden Nano Research Group, University of Southampton
16:00-16:30	Coffee break	
16:30-17:00	Secondary electron energy distribution in HeIM and recent application results	Yuri Petrov Resource Center, St. Petersburg State University
17:00-17:30	The sunrise of He-FIB microscopy: Overview of research activities at EMPA	Fabio La Mattina EMPA
17:30-18:00	Conclusion / Discussion	
19:00	Dinner	

Registration ORION® User Meeting Twente 2012

Please register until 27th of January 2012 online:

<http://www.zeiss.de/C1256E4600305472/allBySubject/AD70F153751848CAC12579660032B0A4>

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Deadline for registration: 27th of January 2012

